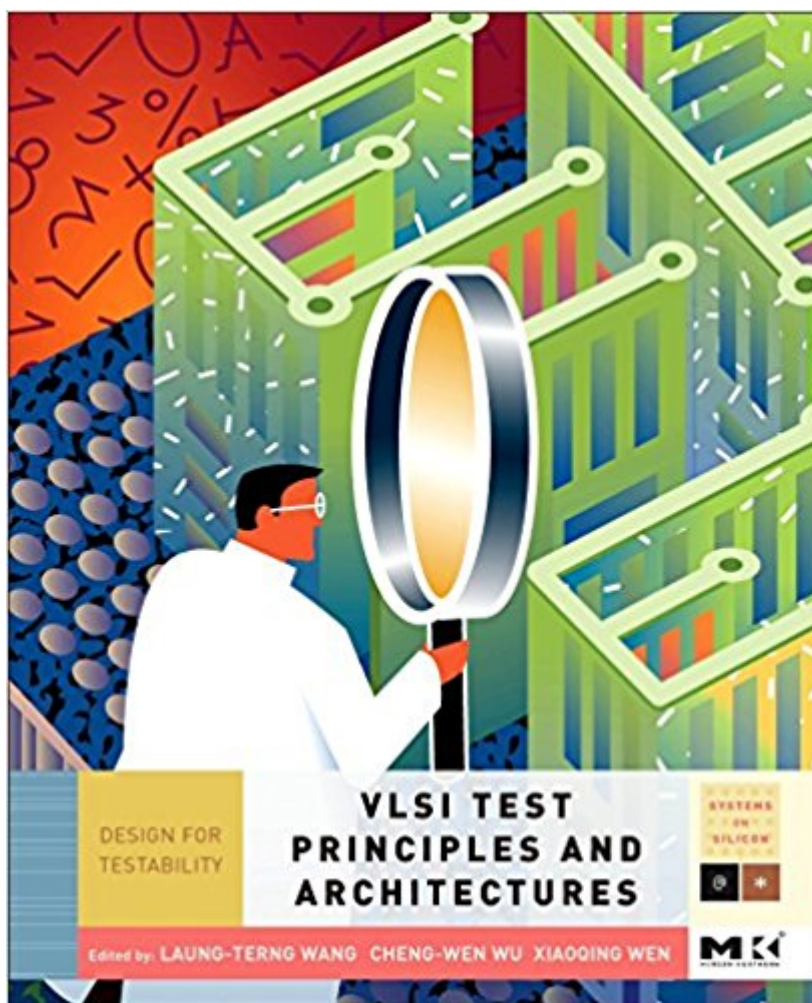


The book was found

VLSI Test Principles And Architectures: Design For Testability (The Morgan Kaufmann Series In Systems On Silicon)



Synopsis

This book is a comprehensive guide to new DFT methods that will show the readers how to design a testable and quality product, drive down test cost, improve product quality and yield, and speed up time-to-market and time-to-volume. Most up-to-date coverage of design for testability. Coverage of industry practices commonly found in commercial DFT tools but not discussed in other books. Numerous, practical examples in each chapter illustrating basic VLSI test principles and DFT architectures.

Book Information

Series: The Morgan Kaufmann Series in Systems on Silicon

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Customer Reviews

In the era of large systems embedded in a single system-on-chip (SOC) and fabricated continuously shrinking technologies, it is important to ensure correct behavior of the whole system. Electronic design and test engineers of today have to deal with these complex and heterogeneous systems (digital, mixed-signal, memory), but few have the possibility to study the whole field in a detailed and deep way. This book provides an extremely broad knowledge of the discipline, covering the fundamentals in detail, as well as the most recent and advanced concepts. Michel Renovell, Laboratoire d'Informatique, de Robotique et de Microélectronique de Montpellier (LIRMM), Montpellier, France This book combines in a unique way insight into industry practices commonly found in commercial DFT tools but not discussed in textbooks, and a sound treatment of

the future fundamentals. The comprehensive review of future test technology trends, including self-repair, soft error protection, MEMS testing, and RF testing, leads students and researchers to advanced DFT research. Hans-Joachim Wunderlich, University of Stuttgart, Germany
Recent advances in semiconductor manufacturing have made design for testability (DFT) an essential part of nanometer designs. I am pleased to find a DFT textbook of this comprehensiveness that can serve both academic and professional needs. Andre Ivanov, University of British Columbia, Canada
This is the most recent book covering all aspects of digital systems testing. It is a “must read” for anyone focused on learning modern test issues, test research, and test practices. Kewal K. Saluja, University of Wisconsin-Madison
By covering the basic DFT theory and methodology on digital, memory, as well as analog and mixed-signal (AMS) testing, this book stands out as one best reference book that equips practitioners with testable SOC design skills. Yihe Sun, Tsinghua University, Beijing, China

The most up-to-date coverage available of VLSI Testing and Design-for-Testability!

I co-authored a chapter, so I am biased. But I use this book in my graduate test class. It is an excellent text for covering all of the fundamentals of integrated circuit testing - basic design-for-test, and algorithms for test generation and fault simulation.

I have been reading this book for my new role as a DFT Engineer. I must say the concept in this book are very practical. I have been using this book as a reference book along side the requirements of the chip and it has been an invaluable resource. I will definitely recommend this book to anyone trying to understand DFT principles or use it as a reference as part of DFT engineer role. Cheers...

This is a great book for Test/DFT engineers and EDA engineers developing test tool. It gives a thorough review of lot of concepts and techniques employed in practice which cannot be found if you look at a general testing book. This also makes it an excellent resource to prepare for interviews.

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